

22.04.2021



ON THE PERFORMANCE AND USE OF THE LARGE AREA MULTI-JUNCTION SOLAR ARRAY TESTER: HIGHLIGHT SAT

INTRODUCTION / TOC



Concept of our metrological tool

Characteristics and capabilities of the tool

Design and manufacturing process of our filters

Use cases and calibration of the tool in production

Testing 3J and the 5J / 6J challenge

CONCEPT

THE NEED

- Measure large area (circa 8 -12 m²) multi-junction solar arrays
- Ensure that each junction is optically pumped as it would in space
- Ensure the highest uniformity of the light source over measurement area
- Simulate Solar spectrum in space AM0 or its equivalent

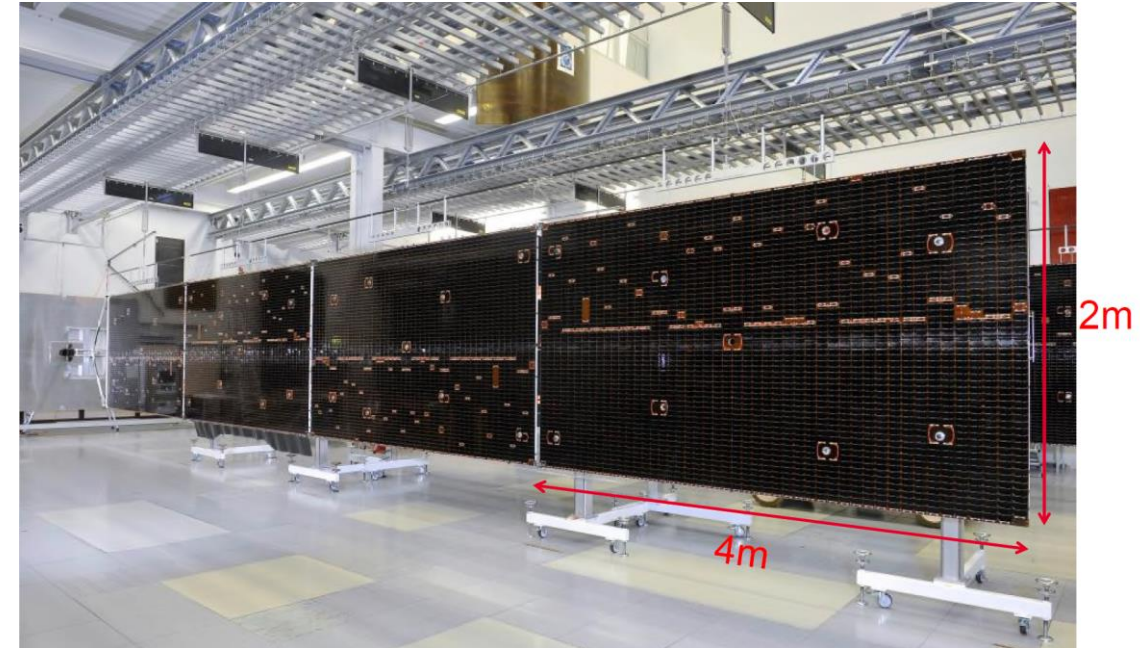


Photo courtesy of Airbus Space & Defence

THE BUILDING BLOCK - STANDARD 1 J TESTER



Light box simulates the AM 1.5G spectrum

Spectral control & uniformity (< 1%)

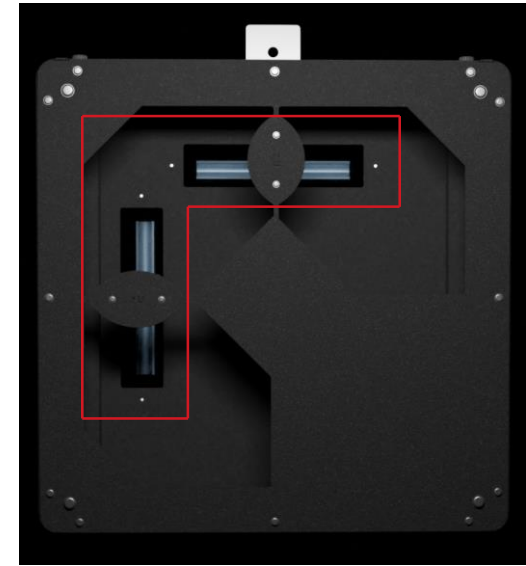
- Customized interferential filters
- High density plasma Xenon flash tubes

Uniformity of Irradiance (< 1%)

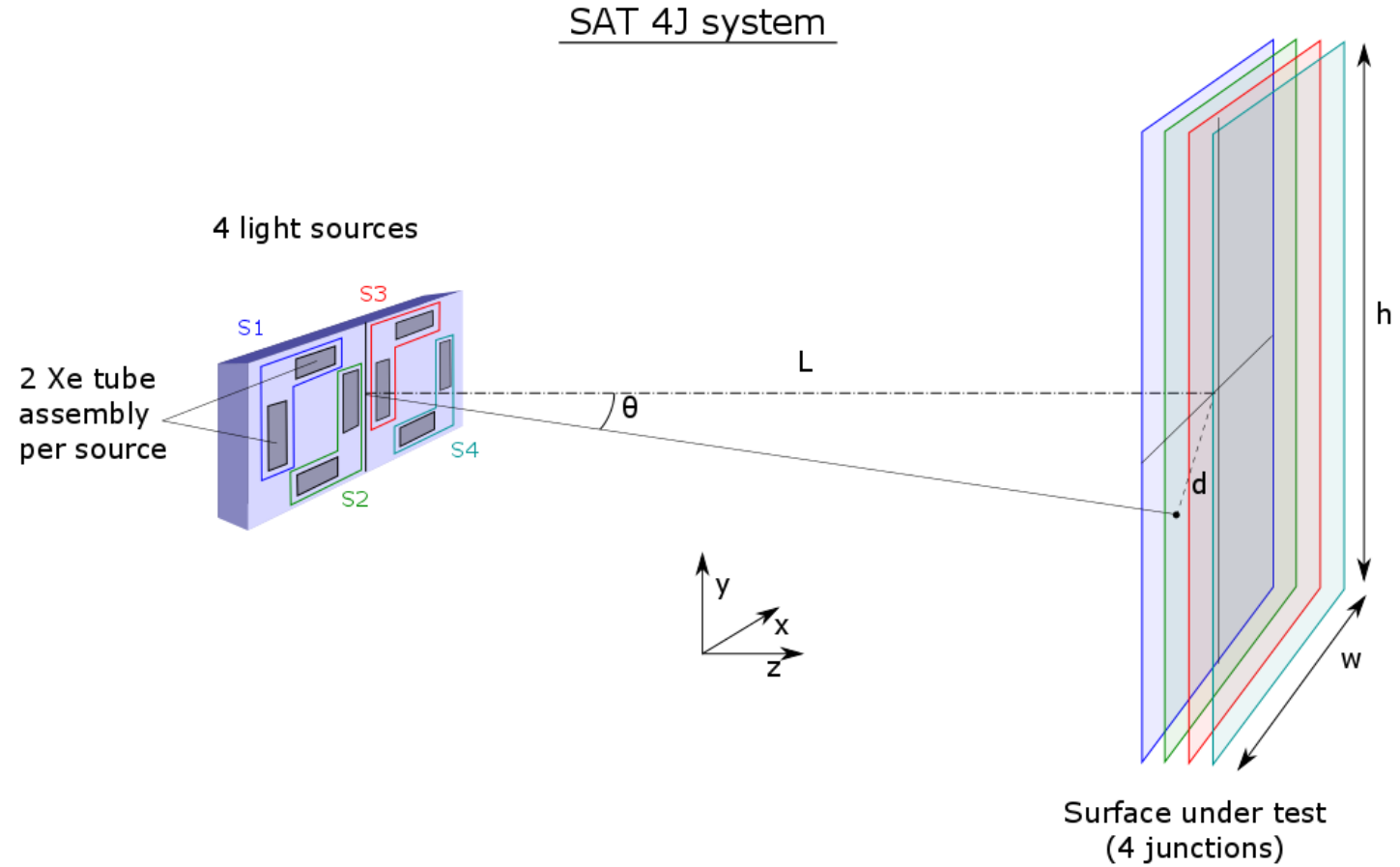
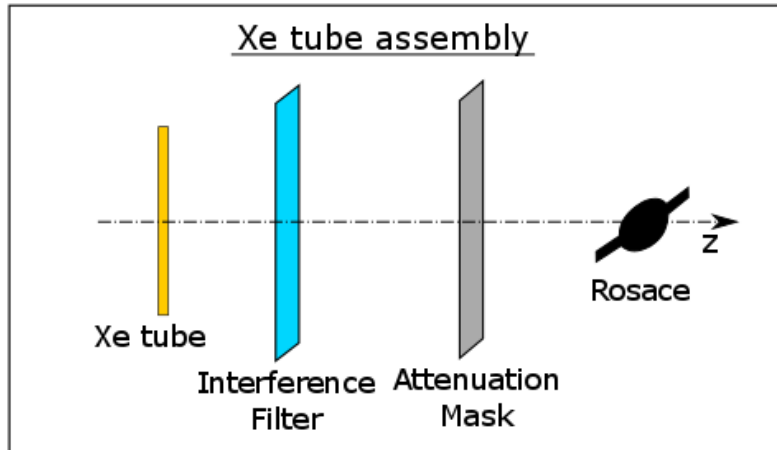
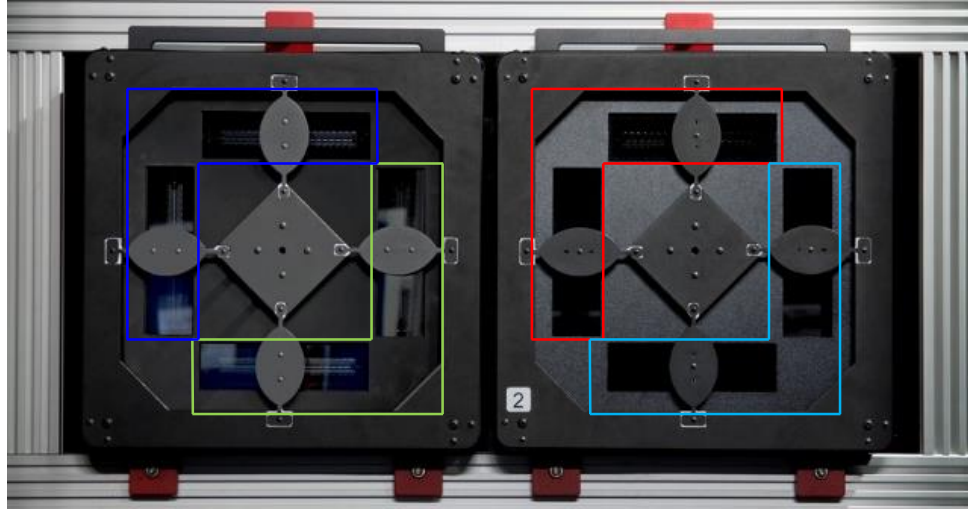
- Advanced uniformity mask (cross/rosette)

Pulse Stability (< 1% LTI)

4 irradiance channel e-load with < 0.1% precision



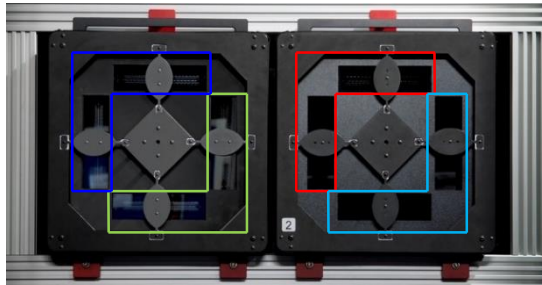
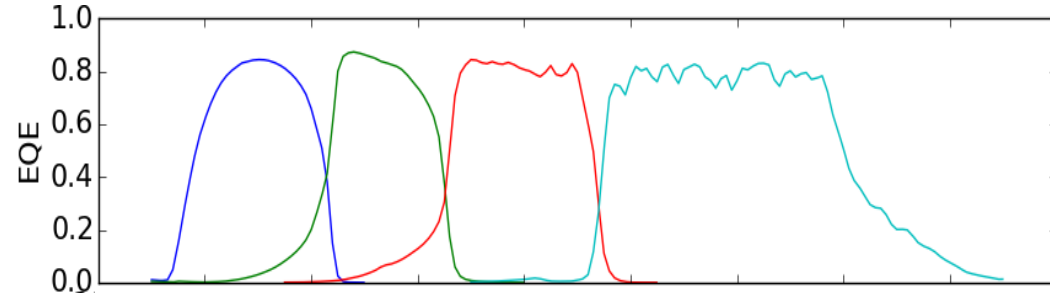
THE 4J TESTER



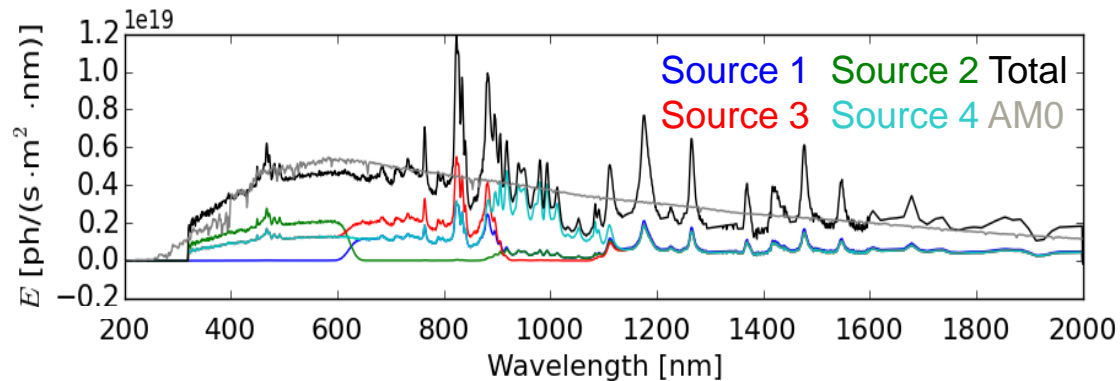
CHARACTERISTICS

TYPICAL DESIGN FOR A 4J SYSTEM

Simulator spectra matching 4 CoCell Ref. Currents



Spectrum calibration within 0.3% of target reference



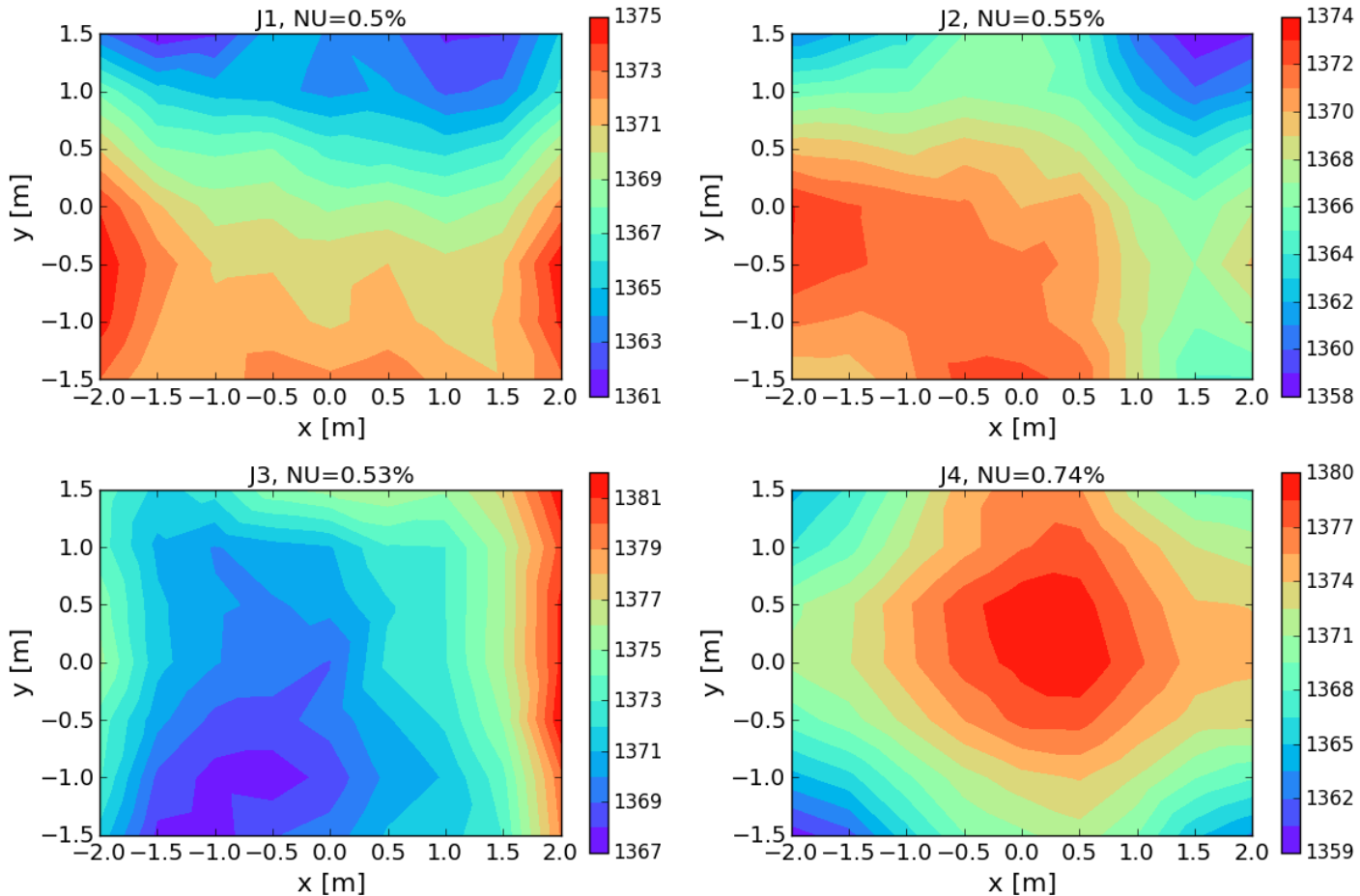
	CoCell currents [mA]							
	1SUN at 8 m				0.1 SUN at 8 m			
	I_1	I_2	I_3	I_4	I_1	I_2	I_3	I_4
Reference	411.4	447.3	443.8	513.3	41.14	44.73	44.38	51.33
Measured	410.4	447.1	444.7	513.0	41.17	44.73	44.39	51.31
δI [%]	-0.25	-0.04	0.20	-0.05	0.08	-0.01	0.02	-0.04

NON UNIFORMITY (NU) OF IRRADIANCE

Measured by 4 junctions on a 4m x 3m surface



Measured non uniformities of 4 CoCells



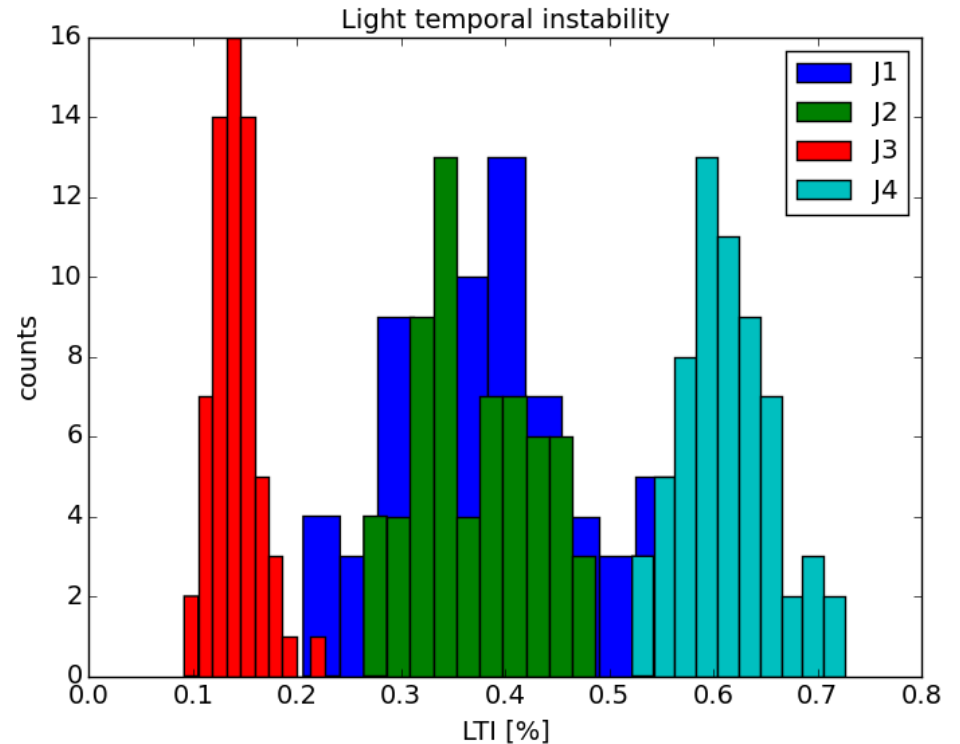
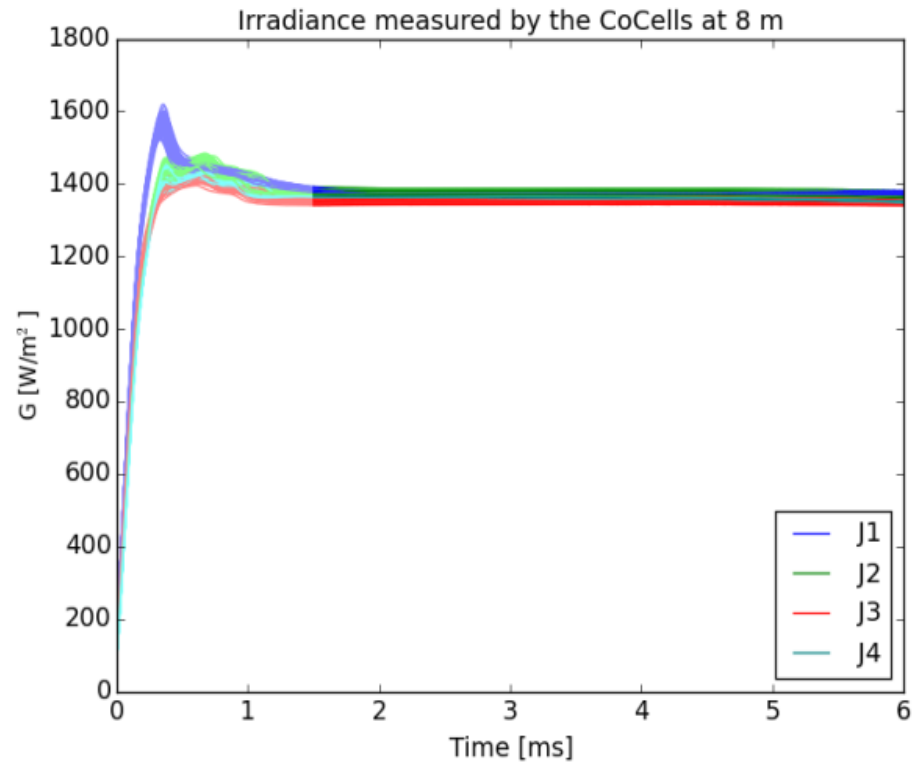
NU < +/- 1% for
3.0m x 4.0m surface

NU < +/- 2% for
3.0m x 4.5m surface

HIGH TEMPORAL STABILITY OF LIGHT PULSE

Light Temporal Instability < 1% for each junctions

Simulator light spectrally stable within 1% according to 4 junctions technology
4 sources controlled individually by feedback loop

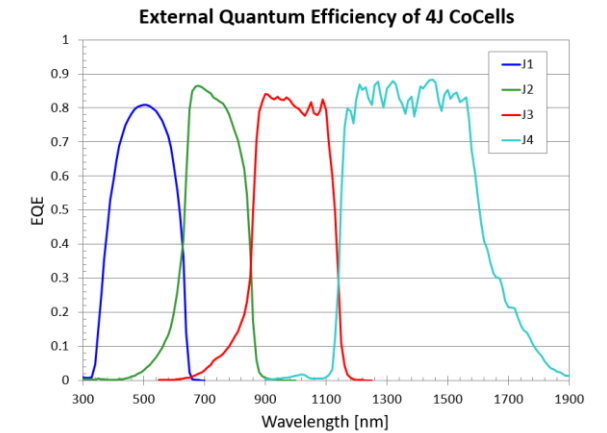
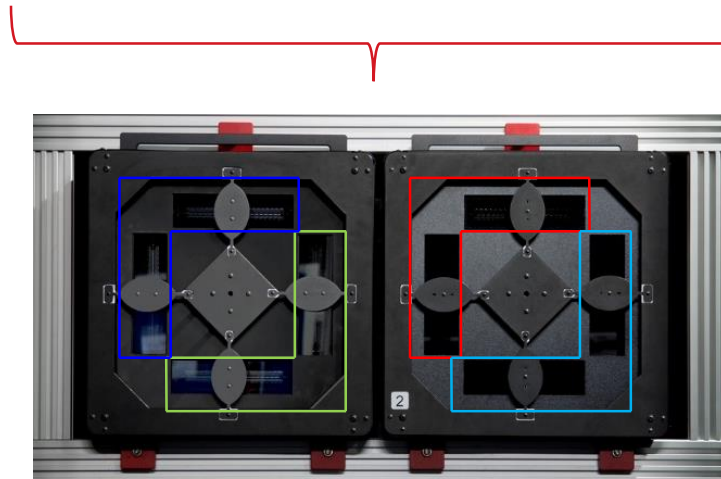
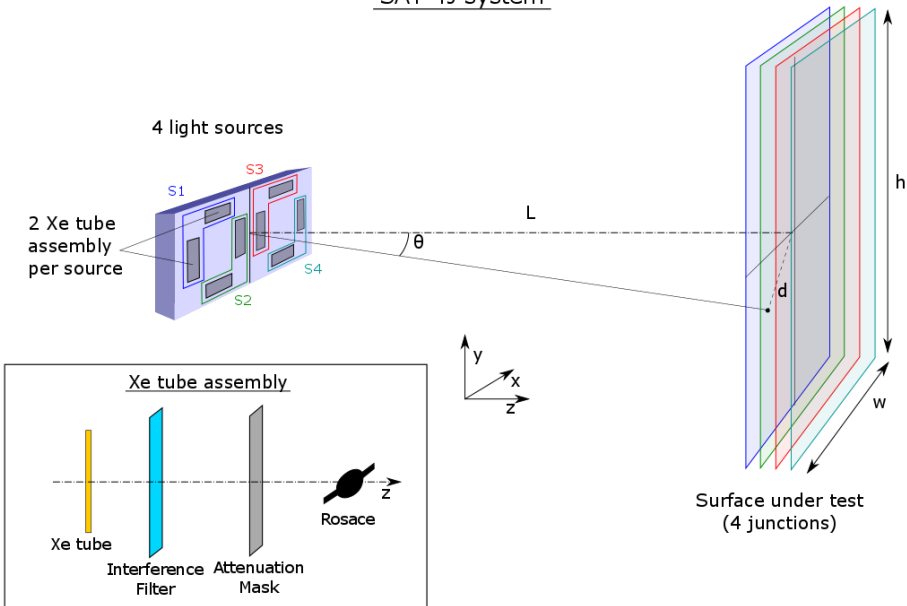


DESIGN & MANUFACTURING

THE MODEL BEHIND OUR SIMULATIONS

$$I_{j,\theta} = A_j \sum_i \int E_{Xe}(\lambda) \cdot T_i(\lambda, \theta) \cdot SR_j(\lambda) d\lambda$$

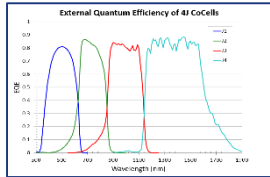
SAT 4J system



DESIGN STEP 1 – INITIAL FILTER DESIGN

Inputs

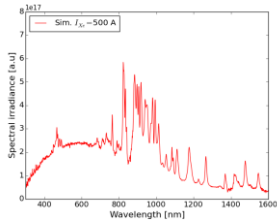
Quantum efficiency of co-cells



Reference currents

$$I_{ref1}, I_{ref2}, I_{ref3}, I_{ref4}$$

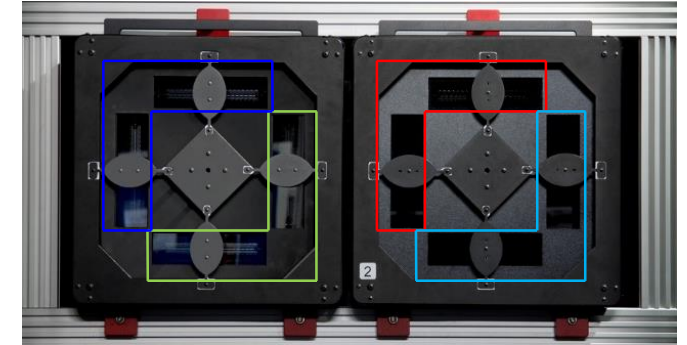
Xe spectral irradiance at fixed nominal operating point



Pasan's Simulation environment

- ❖ $I_{j\theta} = A_j \sum_i \int E_{Xe}(\lambda) \cdot T_i(\lambda, \theta) \cdot SR_j(\lambda) d\lambda$
- ❖ Set $\theta = 0$; Along optical axis
- ❖ Iterative algorithm $\text{Min}(I_{refi} \text{ vs } I_{calci})$

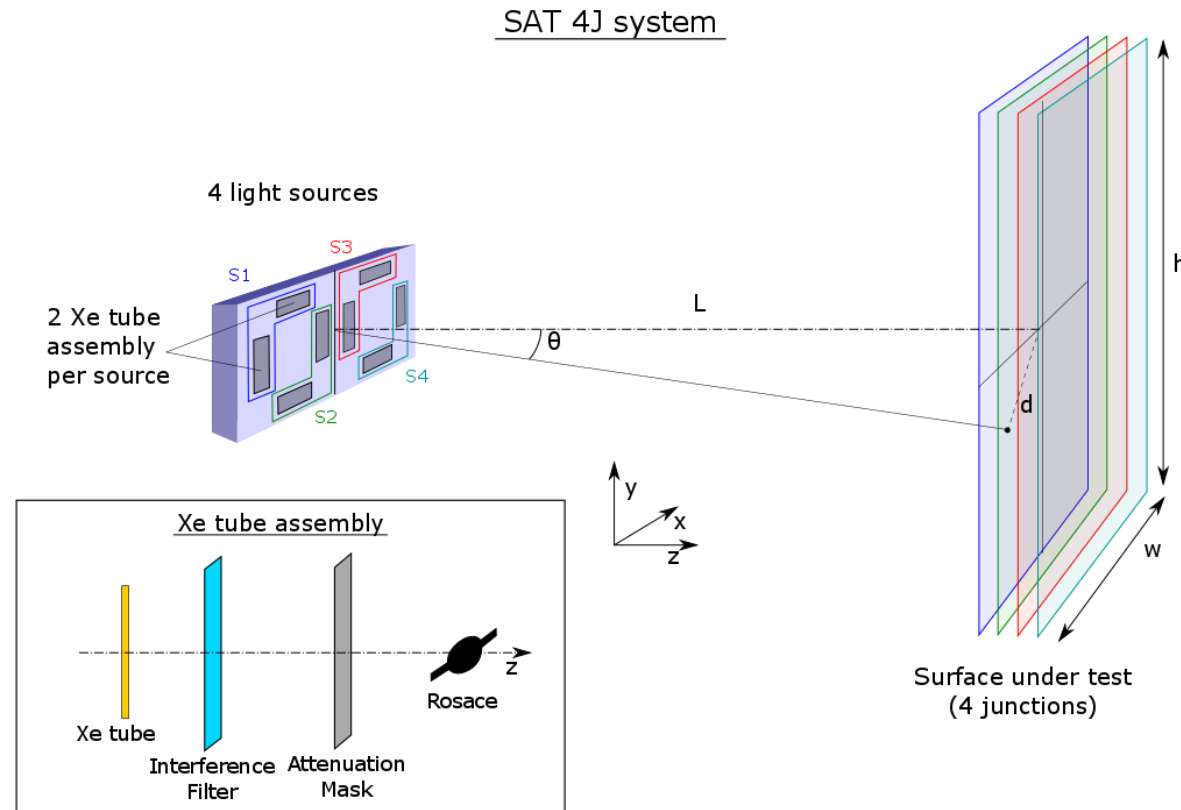
Outputs



An initial guess of the filter design parameters

ANGULAR DEPENDENCE OF FILTERS

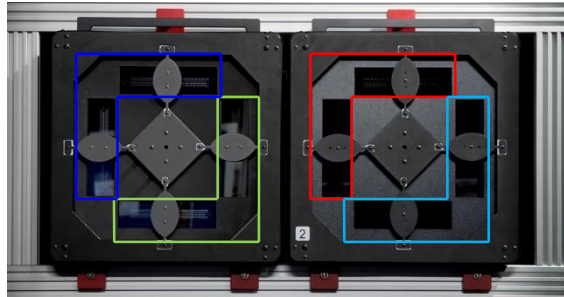
Non-uniformity due to angular dependence of interference filters modifies transmission at different points in the plane



DESIGN STEP 2 – OPTIMIZED SPATIAL UNIFORMITY

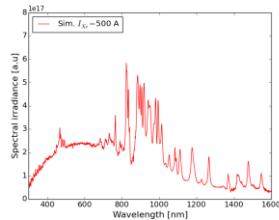
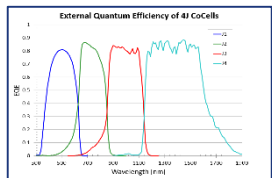
Inputs

Theta = 0



Reference currents

$I_{ref1}, I_{ref2}, I_{ref3}, I_{ref4}$

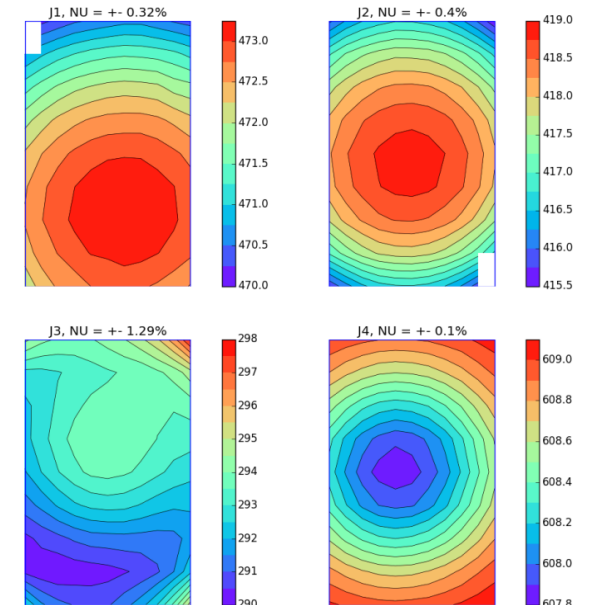


Pasan's Simulation environment

- ❖ $I_j = \int E_{Xe}(IXe, \lambda, \theta) \cdot T(\lambda) \cdot SRj(\lambda) d\lambda$
- ❖ $\text{Min}(I_{rev} \text{ vs } I_{calc})$ as a function of θ

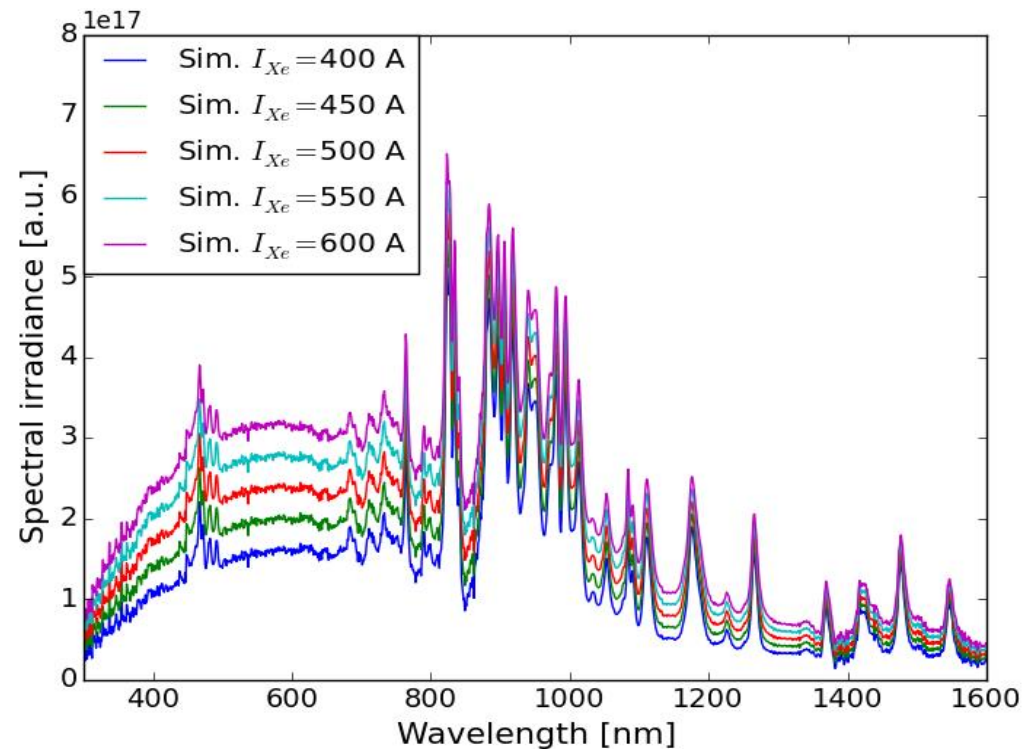
Outputs

- Final filter design
- A map of the non-uniformity
- **Simulated NU < 2%**



MANUFACTURING SYSTEM QUALIFICATION

- Filter designed for sources **nominal operation point (500 A current in Xe)**
- Check with supplier simulations and measurements for achievement of design
- **Filters** and **model** have imperfections → Sources operate at **actual set points** (between 400 A & 600A)
- At factor acceptance of the tool find actual operation point with a calibration process



CALIBRATION & USE CASES

CALIBRATION OF TOOL ONCE IN USE

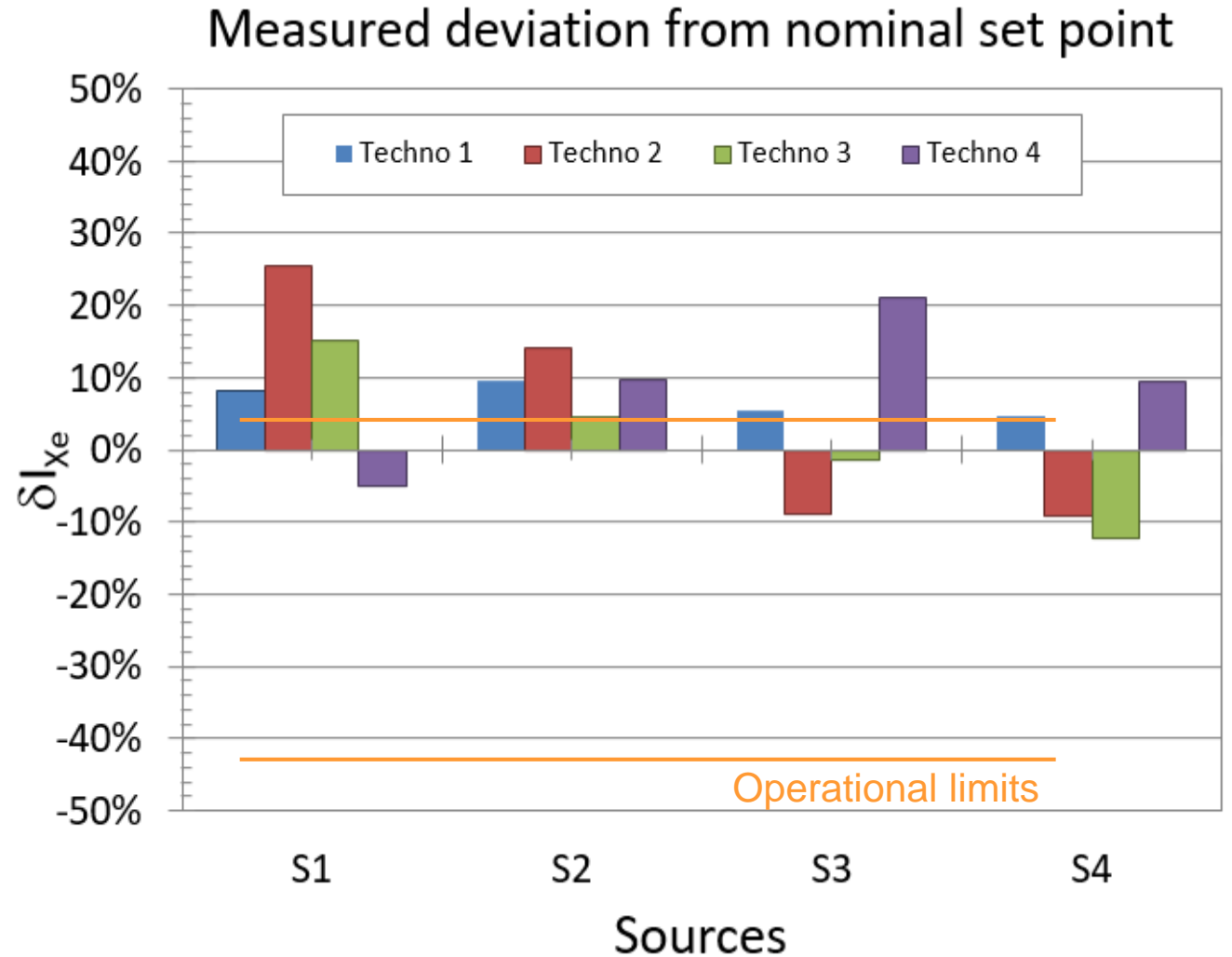


Calibration of the system :

1. Measure I_{SCj} on a RefCells on the optical axis
2. Calibration acceptance criteria $< 0.5\%$ (I vs. I_{Ref1}) on measured RefCell
3. Requires $3 + 2N + 1$ flashes (N = number of junctions)
4. If needed single flash adjustments to reach desired acceptance criteria.
5. Continuous calibration mode also available.

4 DIFFERENT USE CASES

- Actual set points of the sources within operational limits for at least 4 designs of 4J technology
- → Robust design methodology (simulations)
- → Robust manufacturing process



OTHER JUNCTIONS & CHALLENGES

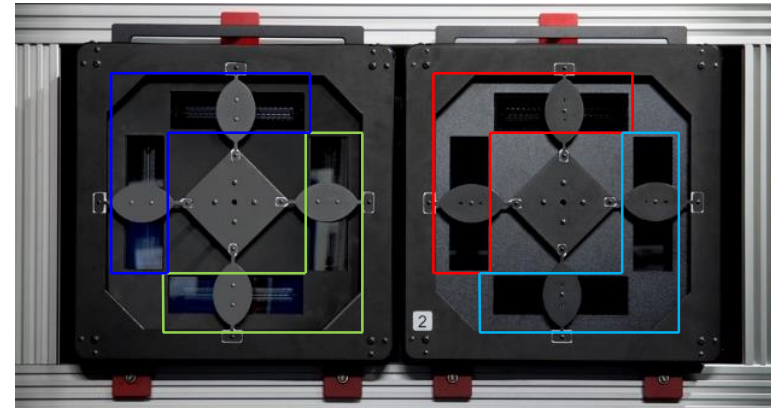
SWITCHING BETWEEN 4J & 3J

Simulation environment is the same

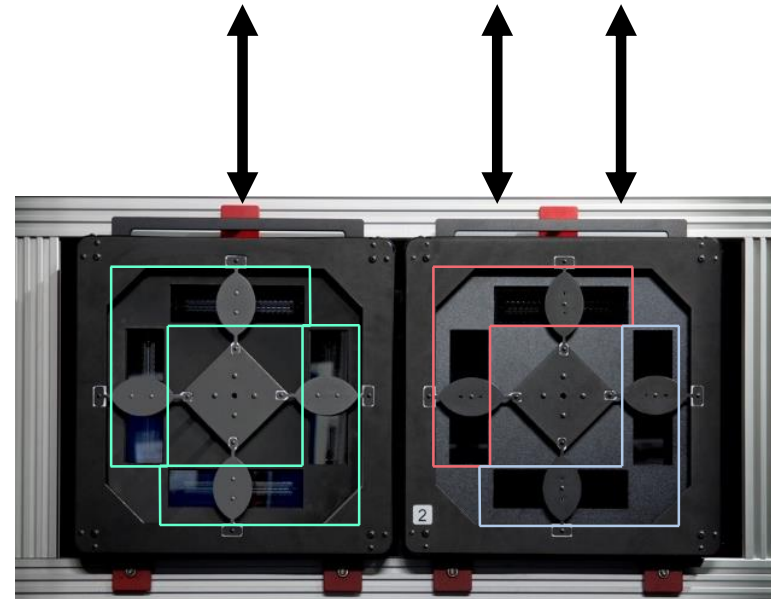
The light box geometry is the same

What changes is the filters (20 minutes to change)

Switch software from 4J to 3J mode



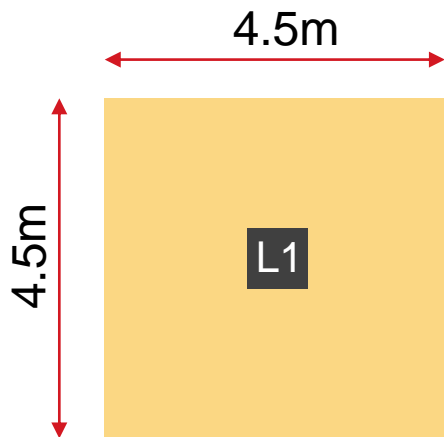
4J
4 Sources



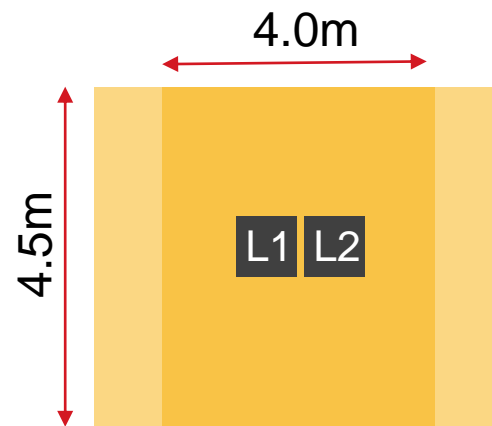
3J
3 Sources

5J AND 6J CHALLENGES

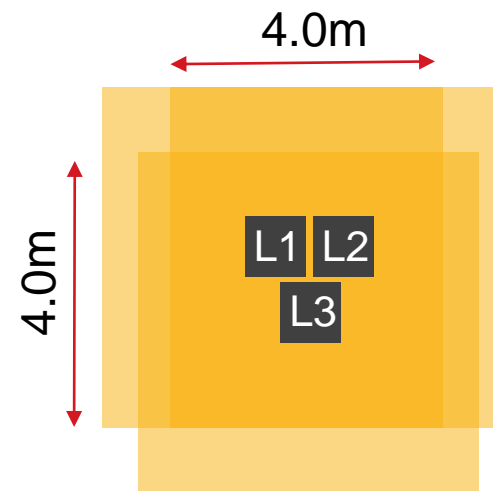
- Adapt simulation environment for 5J & 6J
- Higher number of sources (lamps L1, L2,...) means smaller uniform area
- Higher number of junction means more constraint on filter designs and its angular dependencies incidence on uniform area
- Additional channels needed on e-load (currently limited to 4 channels)



1J/2J systems



$\leq 3J/4J$ systems



5J/6J system

**MERCI
THANK YOU**